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(12) **United States Design Patent**  
**Kister**

(10) **Patent No.:** **US D510,043 S**

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(54) **CONTINUOUSLY PROFILED PROBE BEAM**

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(US)

(73) **Assignee:** **K&S Interconnect, Inc.**, Gilbert, AZ  
(US)

(\*\*) **Term:** **14 Years**

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(51) **LOC (8) Cl.** ..... **10-04**

(52) **U.S. Cl.** ..... **D10/78**

(58) **Field of Search** ..... D10/78; 324/72.5,  
324/537, 750-762

(56) **References Cited**

**U.S. PATENT DOCUMENTS**

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LLP

(57) **CLAIM**

The ornamental design for a continuously profiled probe beam, as shown and described.

**DESCRIPTION**

FIG. 1 shows the continuously profiled probe beam in profile direction.

FIG. 2 is a top view.

FIG. 3 is a side view.

FIG. 4 is an enlarged cross section view indicated in FIG. 1 by section line 4—4.

FIG. 5 is an enlarged cross section view indicated in FIG. 1 by section line 5—5; and,

FIG. 6 is an enlarged cross section view indicated in FIG. 1 by section line 6—6.

**1 Claim, 1 Drawing Sheet**

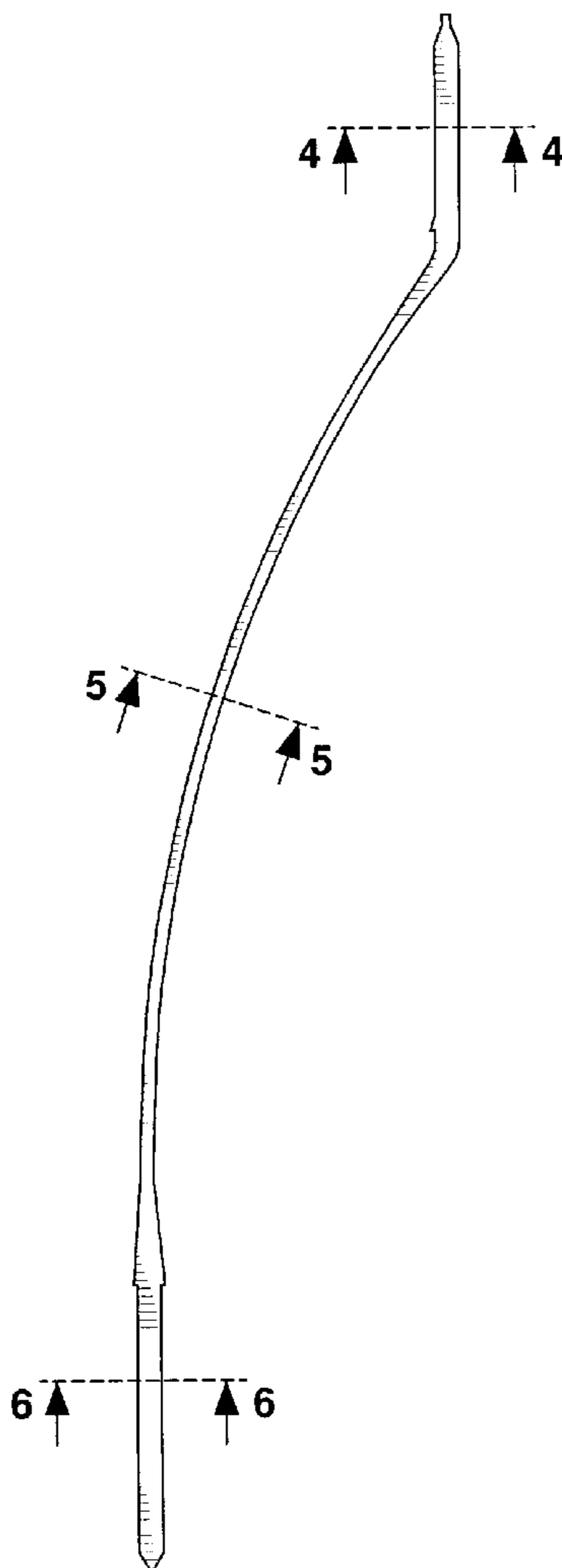


FIG. 2

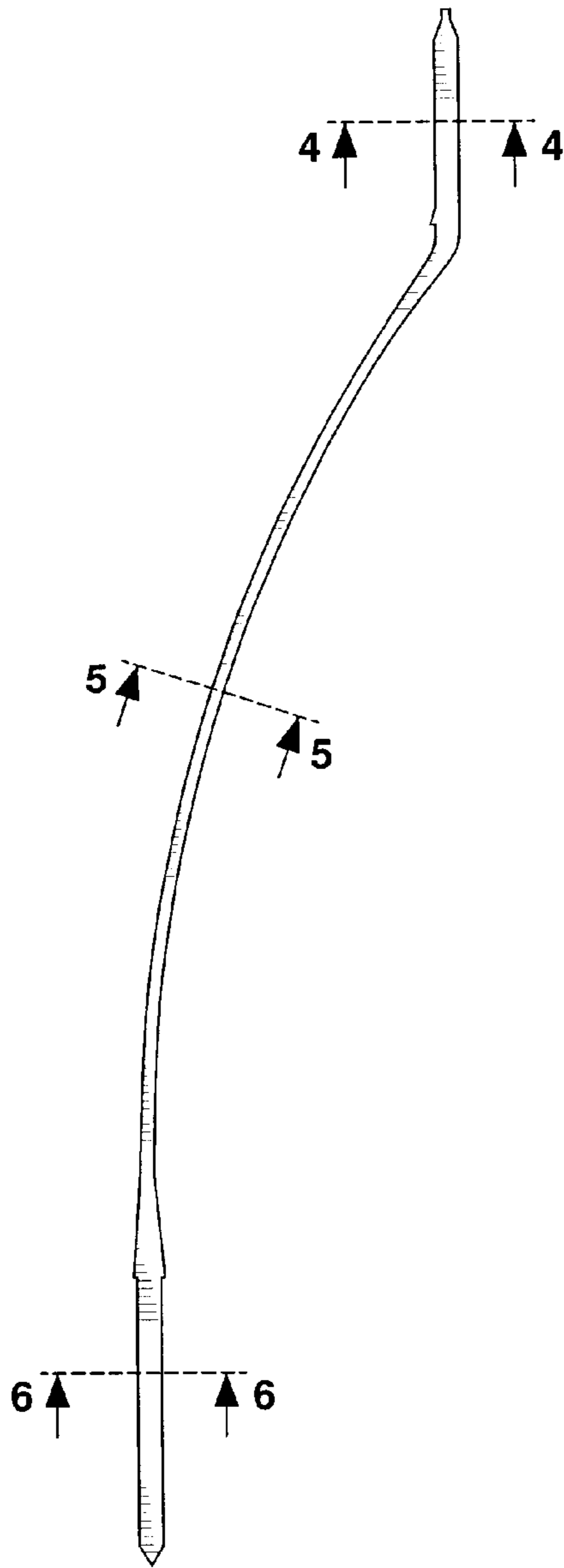
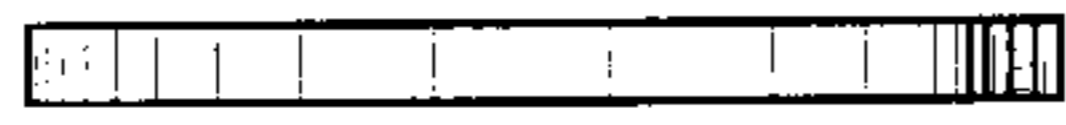


FIG. 1



FIG. 4

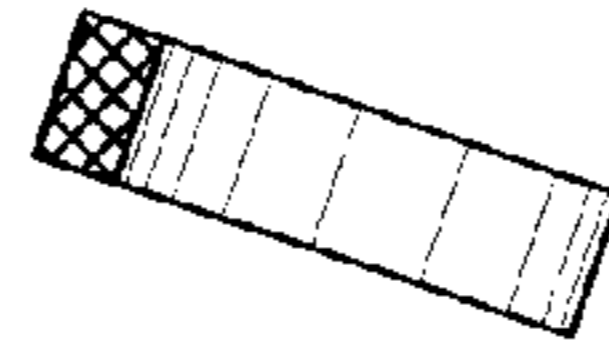


FIG. 5

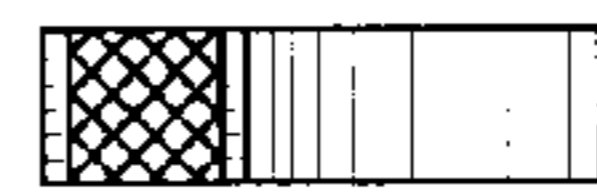


FIG. 6

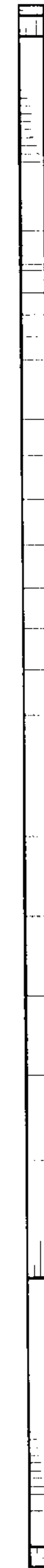


FIG. 3